



Planarity measuring device for thin large-scaled substrates

To be used for measuring flatness, lengths and distances on substrates of thin-glass, sheet metals and thin-films. Tailor-made construction.

Construction

The base plate is made of granite - natural harstone. A mobile gantry, equipped with a cross-slide, carries the reading recorders. Both X- and Y-axis are equipped with length measurement systems.

Measurement tasks

- › Flatness
- › Lengths
- › Distances

Technical specifications

- › Measuring range: X = 1500 mm, Y = 1500 mm
- › Measuring accuracy depending on used measuring Systems

Other dimensions as well as modifications or enhancements are possible.